

N-channel 600 V, 0.092 Ω , 31.5 A MDmesh™ II Power MOSFET in a I²PAKFP package

Datasheet - production data

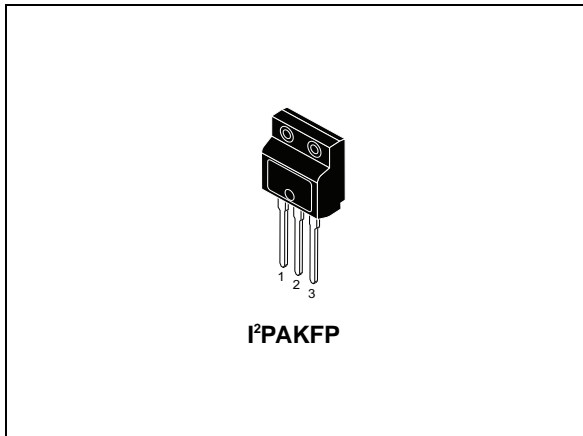
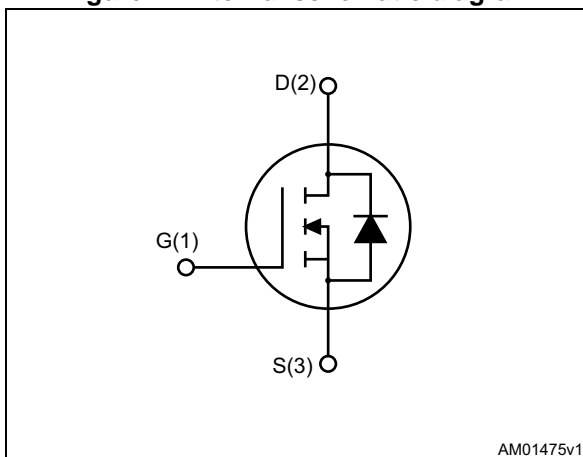


Figure 1. Internal schematic diagram



Features

| Order code | V _{DSS} | R _{DS(on)} | I _D | P _{TOT} |
|-------------|------------------|---------------------|----------------|------------------|
| STFI34NM60N | 600 V | 0.105 Ω | 31.5 A | 40 W |

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

| Order code | Marking | Packages | Packaging |
|-------------|---------|-------------------------------|-----------|
| STFI34NM60N | 34NM60N | I ² PAKFP (TO-281) | Tube |

Contents

| | | |
|----------|---|-----------|
| 1 | Electrical ratings | 3 |
| 2 | Electrical characteristics | 4 |
| | 2.1 Electrical characteristics (curves) | 6 |
| 3 | Test circuits | 8 |
| 4 | Package mechanical data | 9 |
| 5 | Revision history | 11 |

1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|--|---------------------|------------------|
| V_{DS} | Drain-source voltage | 600 | V |
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$ | 31.5 ⁽¹⁾ | A |
| I_D | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 20 ⁽¹⁾ | A |
| $I_{DM}^{(2)}$ | Drain current (pulsed) | 126 | A |
| P_{TOT} | Total dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 40 | W |
| I_{AR} | Max current during repetitive or single pulse avalanche (pulse width limited by T_{jmax}) | 7 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_J = 25\text{ }^\circ\text{C}$, $I_D = I_{AS}$, $V_{DD} = 50\text{ V}$) | 345 | mJ |
| V_{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink ($t=1\text{ s}$; $T_C=25\text{ }^\circ\text{C}$) | 2500 | V |
| $dv/dt^{(3)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(4)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| T_{stg} | Storage temperature | -55 to 150 | $^\circ\text{C}$ |
| T_j | Operating junction temperature | 150 | |

- Limited by package.
- Pulse width limited by safe operating area.
- $I_{SD} \leq 31.5\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, $V_{DS\text{ peak}} \leq V_{(BR)DSS}$, $V_{DD} = 80\% V_{(BR)DSS}$
- $V_{DS} \leq 480\text{ V}$

Table 3. Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|--------------------------------------|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max | 3.1 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-amb max | 62.5 | |

2 Electrical characteristics

($T_{CASE} = 25\text{ °C}$ unless otherwise specified).

Table 4. On/off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|--|---|------|-------|-----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage ($V_{GS} = 0$) | $I_D = 1\text{ mA}$ | 600 | | | V |
| I_{DSS} | Zero gate voltage drain current ($V_{GS} = 0$) | $V_{DS} = 600\text{ V}$ $V_{DS} = 600\text{ V}, T_C = 125\text{ °C}$ | | | 1 100 | μA μA |
| I_{GSS} | Gate body leakage current ($V_{DS} = 0$) | $V_{GS} = \pm 25\text{ V}$ | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ | 2 | 3 | 4 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}, I_D = 14.5\text{ A}$ | | 0.092 | 0.105 | Ω |

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------------|-------------------------------------|---|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100\text{ V}, f = 1\text{ MHz}, V_{GS} = 0$ | - | 2722 | - | pF |
| C_{oss} | Output capacitance | | - | 173 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 1.75 | - | pF |
| $C_{oss\text{ eq.}}^{(1)}$ | Equivalent capacitance time related | $V_{GS} = 0, V_{DS} = 0\text{ to }480\text{ V}$ | - | 458 | - | pF |
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 300\text{ V}, I_D = 15.75\text{ A}, R_G = 4.7\text{ }\Omega, V_{GS} = 10\text{ V}$ (see Figure 18 and 14) | - | 18 | - | ns |
| t_r | Rise time | | - | 36 | - | ns |
| $t_{d(off)}$ | Turn-off delay time | | - | 104 | - | ns |
| t_f | Fall time | | - | 73 | - | ns |
| Q_g | Total gate charge | $V_{DD} = 480\text{ V}, I_D = 31.5\text{ A}$ $V_{GS} = 10\text{ V}$ (see Figure 15) | - | 84 | - | nC |
| Q_{gs} | Gate-source charge | | - | 14 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 45 | - | nC |
| R_G | Intrinsic gate resistance | $f = 1\text{ MHz}, \text{ gate DC Bias} = 0$ test signal level = 20 mV open drain | - | 2.9 | - | Ω |

1. $C_{oss\text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|------|
| I_{SD} | Source-drain current | | - | | 31.5 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 126 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD}= 31.5 \text{ A}, V_{GS}=0$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD}= 31.5 \text{ A}, V_{DD}= 60 \text{ V}$ $di/dt = 100 \text{ A}/\mu\text{s}$, (see Figure 16) | - | 412 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 8 | | nC |
| I_{RRM} | Reverse recovery current | | - | 39 | | A |
| t_{rr} | Reverse recovery time | $I_{SD}= 12 \text{ A}, V_{DD}= 60 \text{ V}$ $di/dt=100 \text{ A}/\mu\text{s}$, $T_j=150 \text{ }^\circ\text{C}$ (see Figure 16) | - | 490 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 10 | | nC |
| I_{RRM} | Reverse recovery current | | - | 43 | | A |

1. Pulse width limited by safe operating area
2. Pulsed: Pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

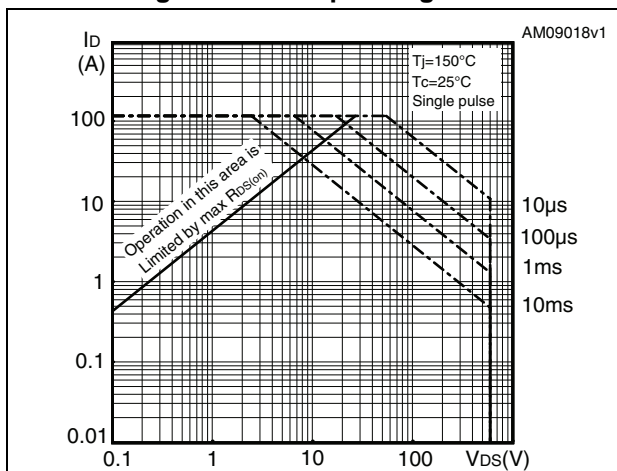


Figure 3. Thermal impedance

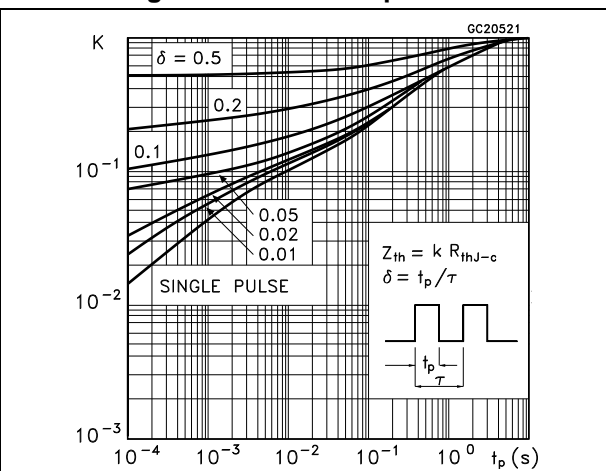


Figure 4. Output characteristics

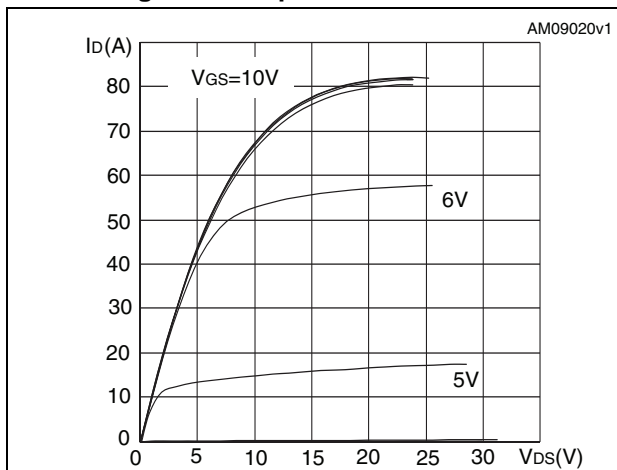


Figure 5. Transfer characteristics

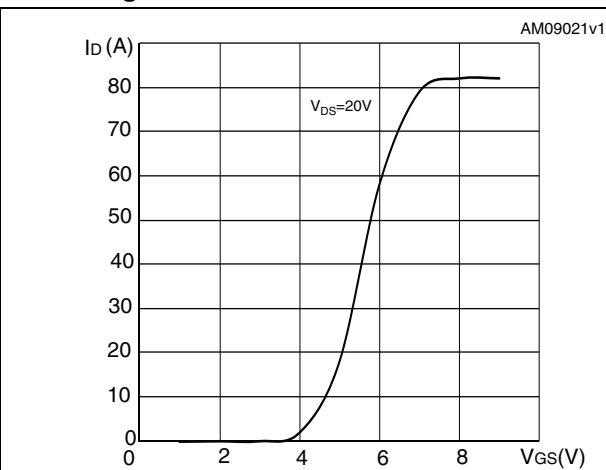


Figure 6. Gate charge vs gate-source voltage

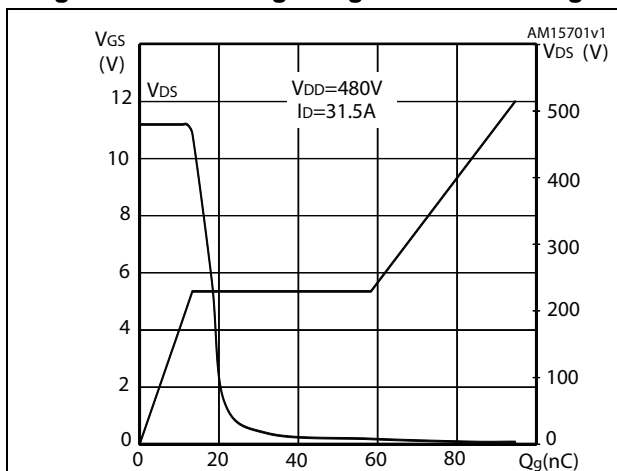


Figure 7. Static drain-source on-resistance

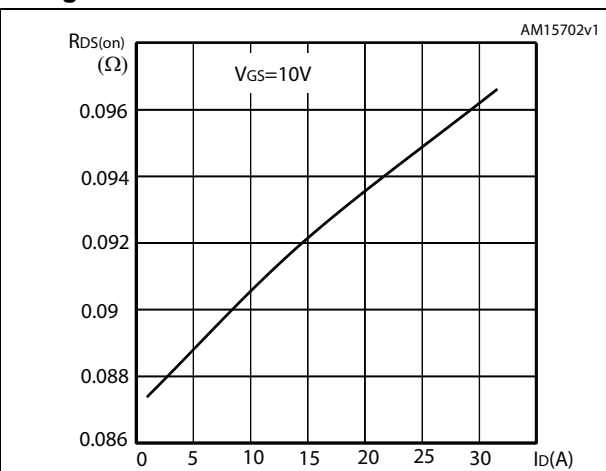


Figure 8. Capacitance variations

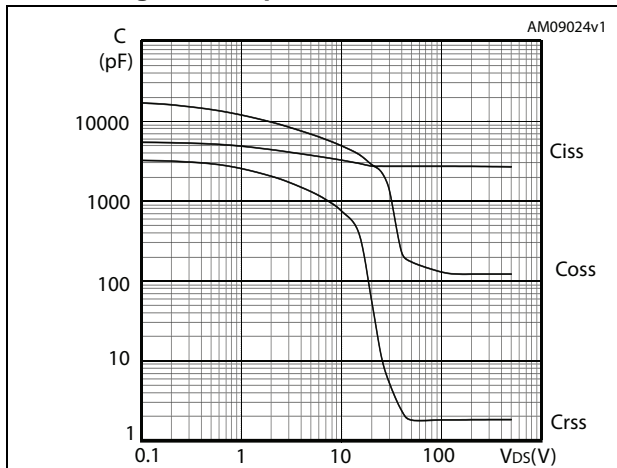


Figure 9. Output capacitance stored energy

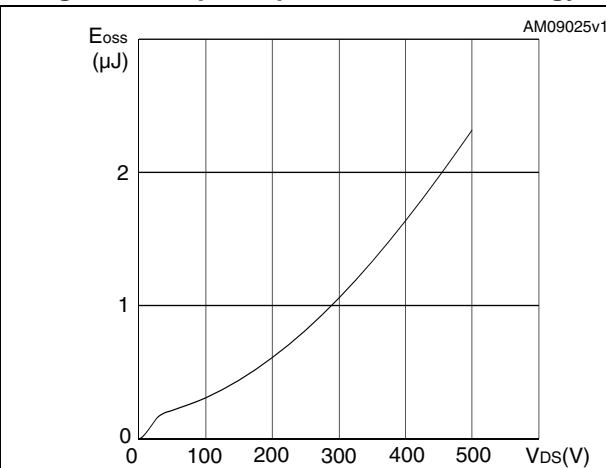


Figure 10. Normalized gate threshold voltage vs temperature

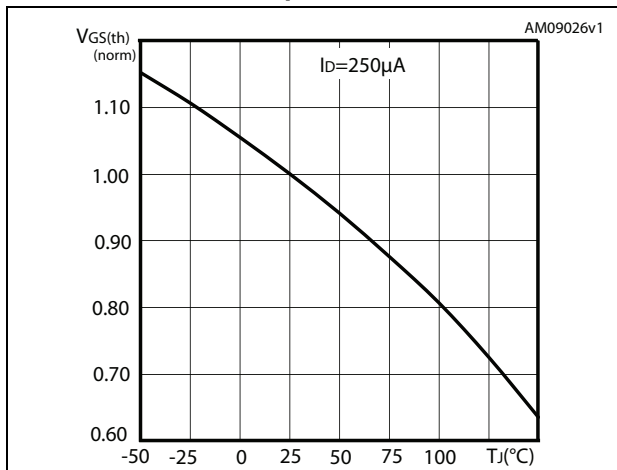


Figure 11. Normalized on-resistance vs temperature

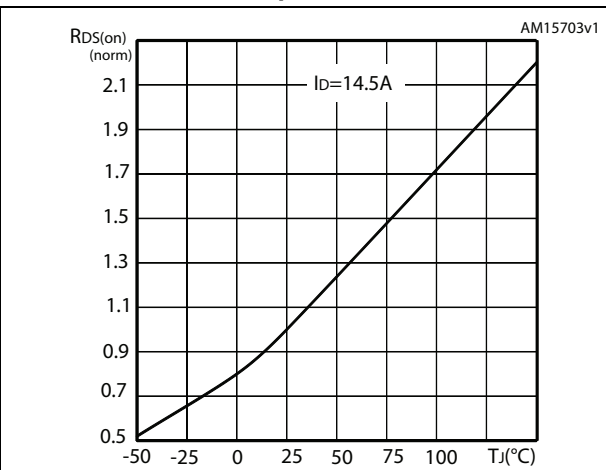


Figure 12. Normalized B_{VDS} vs temperature

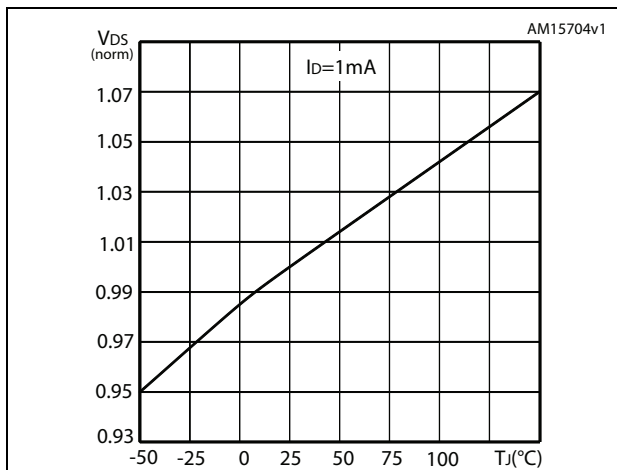
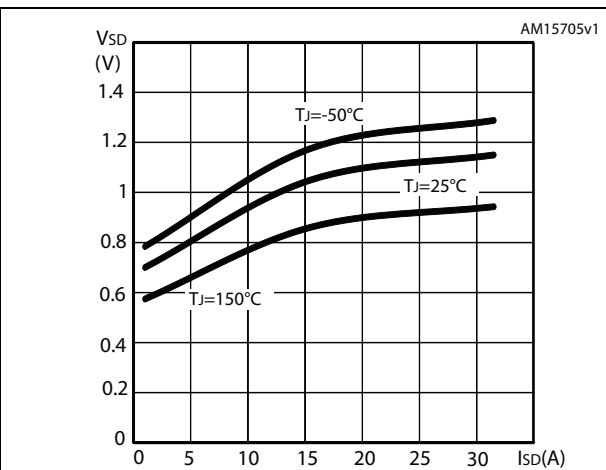


Figure 13. Source-drain diode forward characteristics



3 Test circuits

Figure 14. Switching times test circuit for resistive load



Figure 15. Gate charge test circuit



Figure 16. Test circuit for inductive load switching and diode recovery times



Figure 17. Unclamped inductive load test circuit



Figure 18. Unclamped inductive waveform

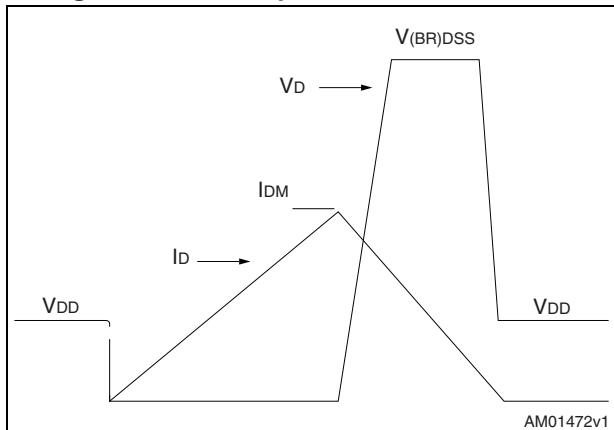
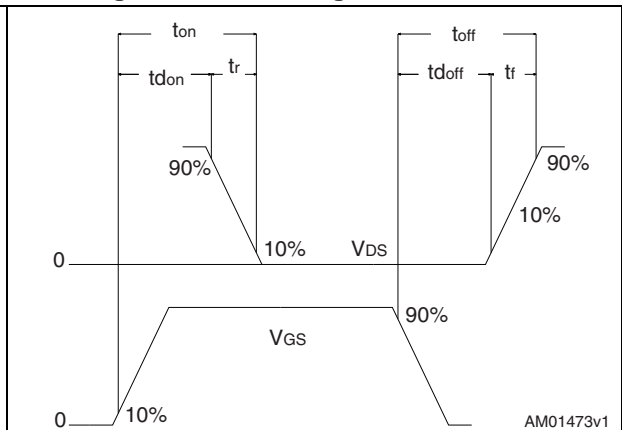


Figure 19. Switching time waveform



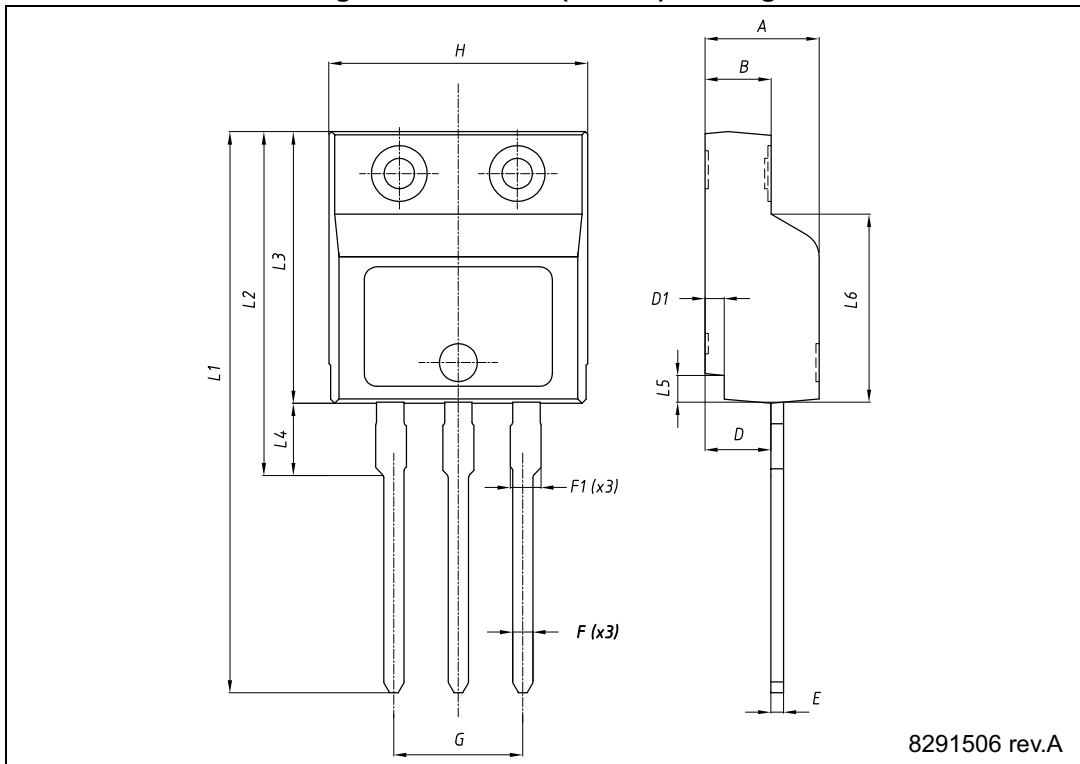
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

Table 7. I²PAKFP (TO-281) mechanical data

| Dim. | mm | | |
|------|-------|------|-------|
| | Min. | Typ. | Max. |
| A | 4.40 | - | 4.60 |
| B | 2.50 | | 2.70 |
| D | 2.50 | | 2.75 |
| D1 | 0.65 | | 0.85 |
| E | 0.45 | | 0.70 |
| F | 0.75 | | 1.00 |
| F1 | | | 1.20 |
| G | 4.95 | | 5.20 |
| H | 10.00 | | 10.40 |
| L1 | 21.00 | | 23.00 |
| L2 | 13.20 | | 14.10 |
| L3 | 10.55 | | 10.85 |
| L4 | 2.70 | | 3.20 |
| L5 | 0.85 | | 1.25 |
| L6 | 7.30 | | 7.50 |

Figure 20. I²PAKFP (TO-281) drawing



8291506 rev.A

5 Revision history

Table 8. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 07-Nov-2011 | 1 | First release. |
| 19-Apr-2012 | 2 | <ul style="list-style-type: none"> – Units in Table 6: Source drain diode have been corrected. – Figure 6: Gate charge vs. gate-source voltage has been updated. – Minor text changes. |
| 16-Jul-2013 | 3 | <ul style="list-style-type: none"> – Modified: title, I_D and Figure 1 in cover page – Modified: I_D for $T_C=20\text{ °C}$ and for $T_C=100\text{ °C}$, I_{DM} in Table 2, note 1, note 3 in Table 2 – Inserted: dv and dt in Table 2 and note 4 in Table 2 – Modified: I_{SD}, I_{SDM} max values in Table 6 and Figure 14, 15, 16 and 17 |

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